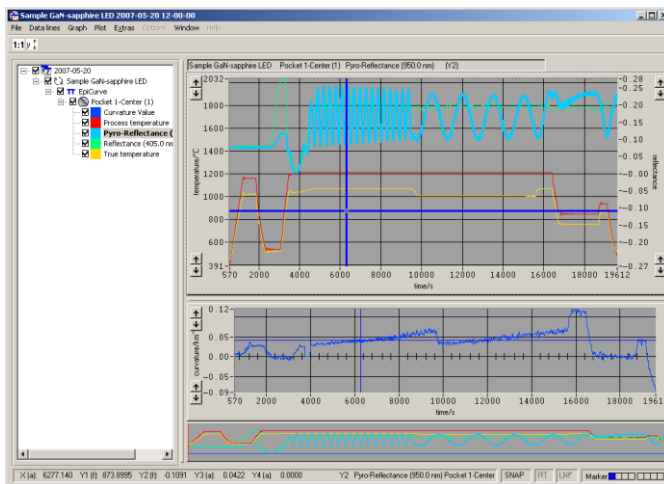


EpiNet 1.10

EpiNet 1.10 ist a control and analysis software for LayTec’s in-situ monitoring tools EpiTT, EpiTwin TT, EpiCurve®TT and EpiCurve®Twin TT. The features incomparable performance and reliability especially for production environments. Version 1.10 has is very user friendly and implements modifications suggested by our customers over the last years. Finally, as common software for all EpiTT, EpiTwinTT and EpiCurve® sensors, the EpiNet software interface remains the same even in case of system upgrade.

For configuration and calibration, the software offers two different user levels (Operator and Advanced) for the different tasks of operators and process engineers. Advanced integration into the epitaxy control software such as AlXact as well as very convenient remote control features from the growth recipe are provided.



The main user screen “EpiNet-Display” offers two graphs displaying reflectance (light blue), temperature (red), curvature (dark blue) and rotation frequency in real-time. Linescans of reflectance and temperature across each wafer and the whole susceptor can be monitored in-situ, too. In multi-wafer systems, the measurement can be taken at different positions on the wafer, providing the user with information about reflectance and temperature gradients across each individual wafer during growth.

Reference data can be loaded in addition to the current measurement.

At the end of the run, automated growth rate fits can be performed, providing wafer selective results in a report file without any additional interaction. The capabilities of the growth rate fit have been further increased, now offering a much faster and even more reliable three parameter fit to obtain growth rate, refractive index and absorption coefficient from any Fabry-Perot oscillation.

Users running older versions can purchase a software upgrade. For further information and for quotation please contact info@laytec.de.